



		Subclass	ISSUE CLASSIFICATION
		Class	

PATENT NUMBER

**U.S. UTILITY Patent Application**

O.I.P.E.  SCANNED <u>SB%</u> Q.A. 	PATENT DATE
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APPLICATION NO. 09/896722	CONT/PRIOR	CLASS 216	SUBCLASS 66	ART UNIT 17467	EXAMINER Ahmed Brown
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1765

## Method to repair localized amplitude defects in a EUV lithography mask blank

PTO-2040  
12/99

**ISSUING CLASSIFICATION**

<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>	<b>DRAWINGS</b>			<b>CLAIMS ALLOWED</b>	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.				<b>NOTICE OF ALLOWANCE MAILED</b>	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent No. _____ _____ _____				<b>ISSUE FEE</b>	
				Amount Due	Date Paid
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.				<b>ISSUE BATCH NUMBER</b>	

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